Search Notes

Appl	ication	/Cont	rol No.

Applicant(s)/Patent under Reexamination

10/710,288

BEYER ET AL.
Art Unit

Examiner

2178

Cong-Lac Huynh

	SEAR	CHED	
Class	Subclass	Date	Examiner
715	500	12/5/2006	CLH
	513	12/5/2006	CLH
	514	12/5/2006	CLH
707	1, 3	12/7/2006	CLH
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
•	DATE	EXMR	
East	12/5/2006	CLH	
ACM	12/5/2006	CLH	
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